



COVENTOR

MEMS Modelling

May 12, 2015

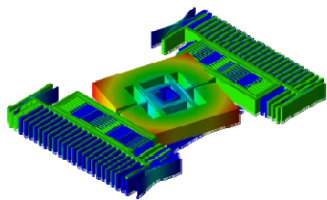
颜军 Jun Yan, Ph.D.
Technical Director – MEMS, Coventor

MEMS Modeling 微机电系统模型

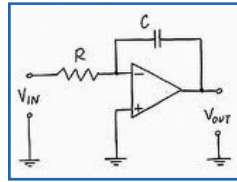
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MEMS Design Automation 微机电系统自动化设计

MEMS+[®] high-order FEA
高阶有限元分析



Cadence Virtuoso[®]



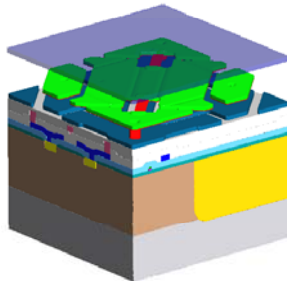
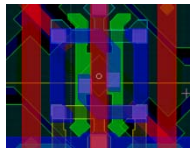
MATLAB Simulink[®]

CoventorWare[®] hybrid FEM/BEM
混合有限元、边界元方法

- Fast simulations for concept exploration and design optimization → **faster time-to-market**
探索方案、优化设计、快速仿真 → 快速市场化
- Integrated MEMS+CMOS design flow and design kits → **enables fabless MEMS/IOT market**
整合MEMS+CMOS设计流程以及设计包
→ 物联网的高效研发
- MEMS multi-physics, nonlinear coupled electro-mechanics 多物理体系、非线性电子 - 机械耦合
- Live Demo 现场案例演示

Virtual Fabrication 工艺模拟

SEMulator3D[®]



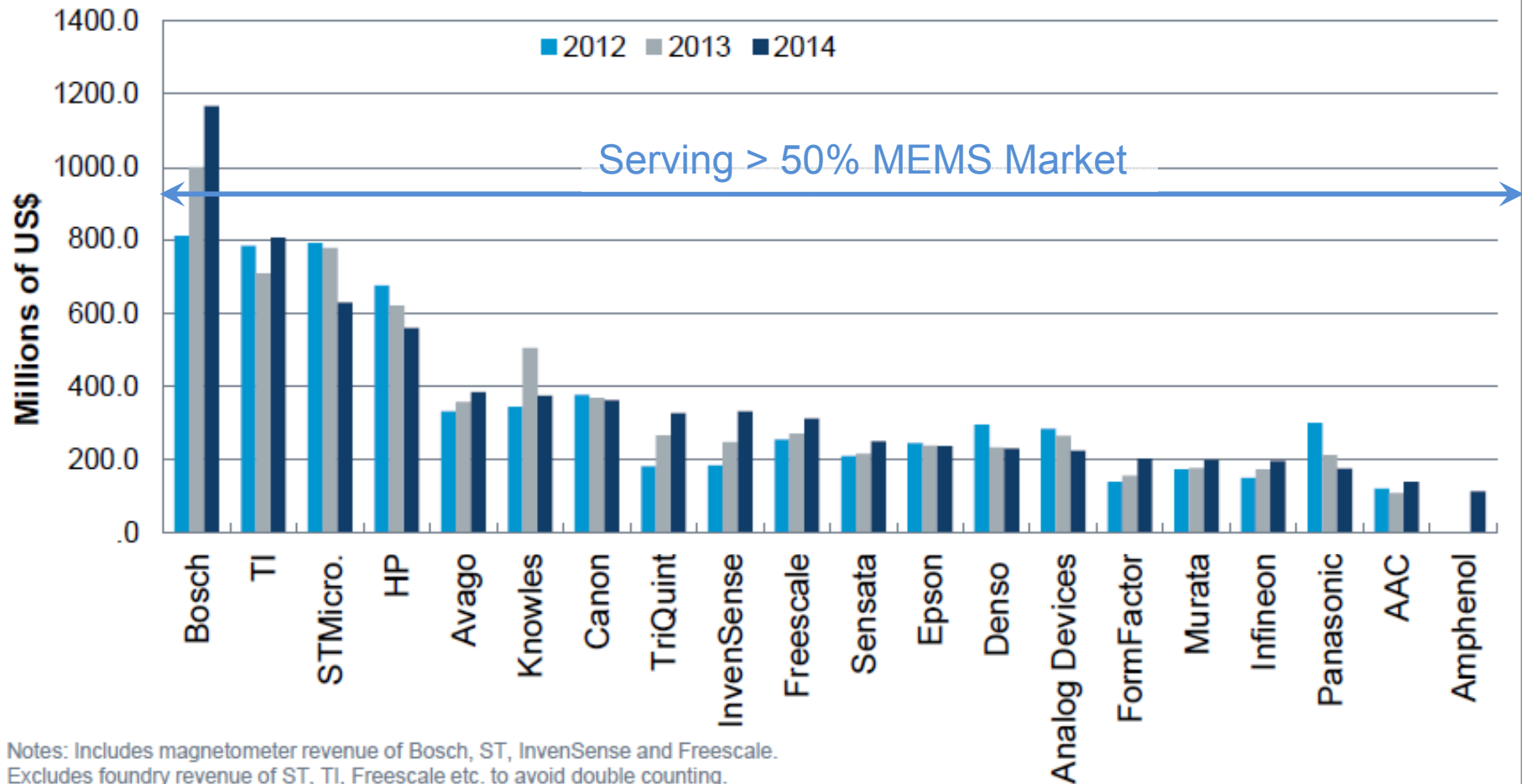
Layer	Material	Thickness (nm)	Process
Substrate	Si	500	MEMS
SiO ₂	SiO ₂	100	MEMS
S1	AlN	10	MEMS
S2	SiO ₂	10	MEMS
S3	AlN	10	MEMS
S4	SiO ₂	10	MEMS
S5	AlN	10	MEMS
S6	SiO ₂	10	MEMS
S7	AlN	10	MEMS
S8	SiO ₂	10	MEMS
S9	AlN	10	MEMS
S10	SiO ₂	10	MEMS
S11	AlN	10	MEMS
S12	SiO ₂	10	MEMS
S13	AlN	10	MEMS
S14	SiO ₂	10	MEMS
S15	AlN	10	MEMS
S16	SiO ₂	10	MEMS
S17	AlN	10	MEMS
S18	SiO ₂	10	MEMS
S19	AlN	10	MEMS
S20	SiO ₂	10	MEMS
S21	AlN	10	MEMS
S22	SiO ₂	10	MEMS
S23	AlN	10	MEMS
S24	SiO ₂	10	MEMS
S25	AlN	10	MEMS
S26	SiO ₂	10	MEMS
S27	AlN	10	MEMS
S28	SiO ₂	10	MEMS
S29	AlN	10	MEMS
S30	SiO ₂	10	MEMS

- Process development → **shorten or avoid in-fab learning cycles**
发展模拟制程 → 缩短或避免在产线上的学习周期
- 3D verification for mask sign-off → **catch design errors before fabrication**
掩膜版的3D验证 → 上产线之前发现、更正设计错误
- **Structured, efficient communication** between designers & fab/foundry 设计-晶圆代工厂之间更有效沟通
- Live Demo 现场案例演示

Coventor Customers Comprise > 50% of the MEMS Market

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Top 20 MEMS IDM and Fabless manufacturers



Notes: Includes magnetometer revenue of Bosch, ST, InvenSense and Freescale.

Excludes foundry revenue of ST, TI, Freescale etc. to avoid double counting.

Source: IHS MEMS Market Tracker – Q1 2015 – Preliminary results

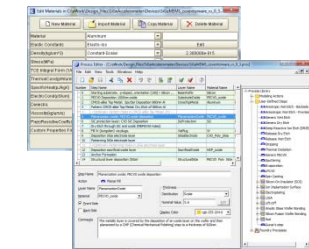
© 2014 IHS

CoventorWare, from 2D Layout to 3D Simulations

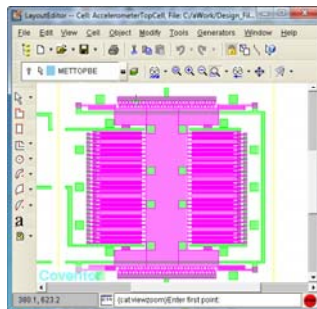
COVENTOR

DESIGNER

ANALYZER

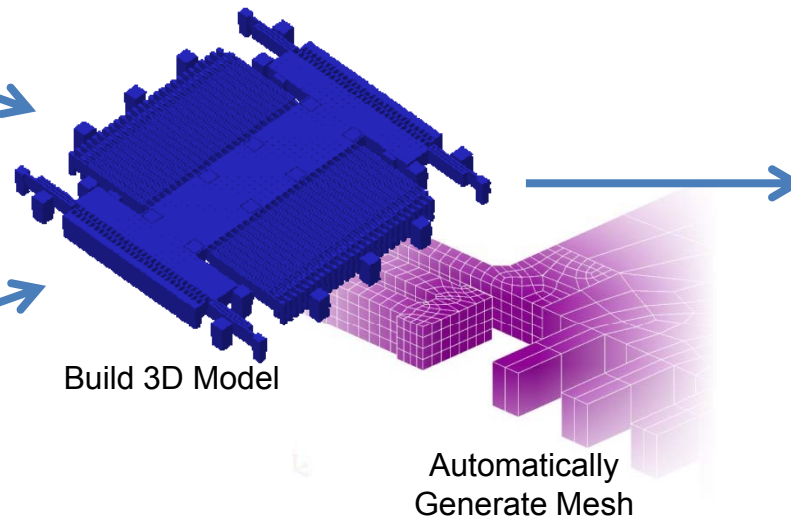


Materials & Process



Create 2D Layout

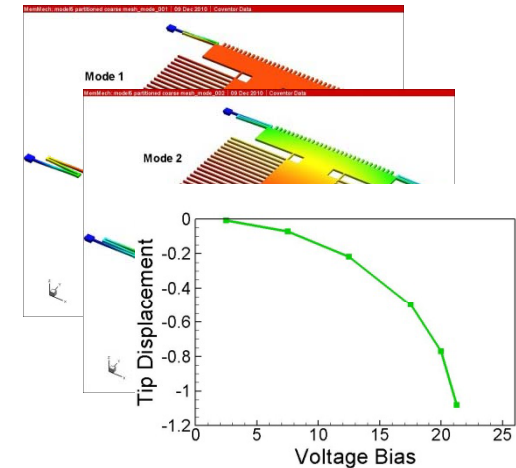
Process-Centric
Design Entry



Build 3D Model

Automatically
Generate Mesh

Preprocessing and Mesh Generation
Optimized for MEMS Geometry



Simulate, Visualize, and Analyze

Hybrid FEM/BEM Suite
of Multi-Physics Field Solvers

Customer Publication with CoventorWare



A Monolithic 9 Degree of Freedom (DOF) Capacitive Inertial MEMS Platform

Ilker E. Ocak*, Daw D. Cheam, Sanchitha N. Fernando, Angel T.H. L. Jaibir Sharma, Geng L. Chua, Bangtao Chen, Alex Y.D. Gu, Navab Singh

Institute of Microelectronics, A*STAR (Agency for Science, Technology and Research)
11 Science Park Road, Singapore Science Park II, Singapore 117602

*Email: ocakie@ime.a-star.edu.sg, Tel: +65 6770 5480, Fax: +65 6770 5481

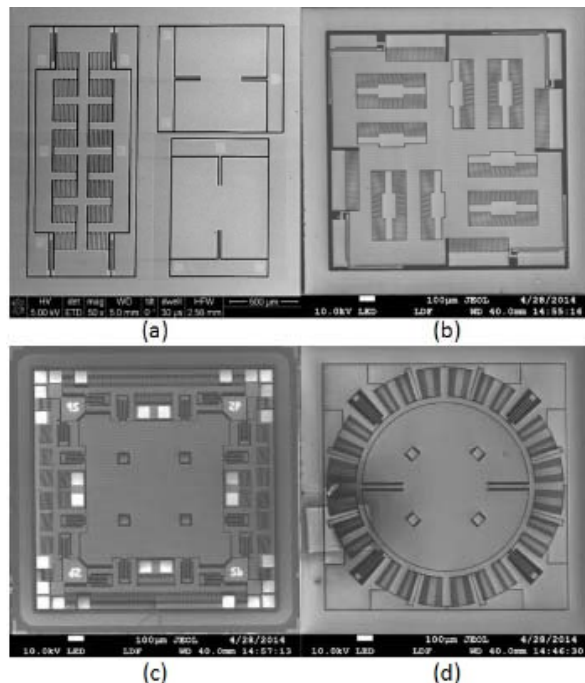


Figure 3: SEM images of fabricated sensors. (a) Three axis Lorentz Force magnetometer (b) Dual axis accelerometer (c) Z-axis tuning fork gyroscope (d) X & Y axis gyroscope

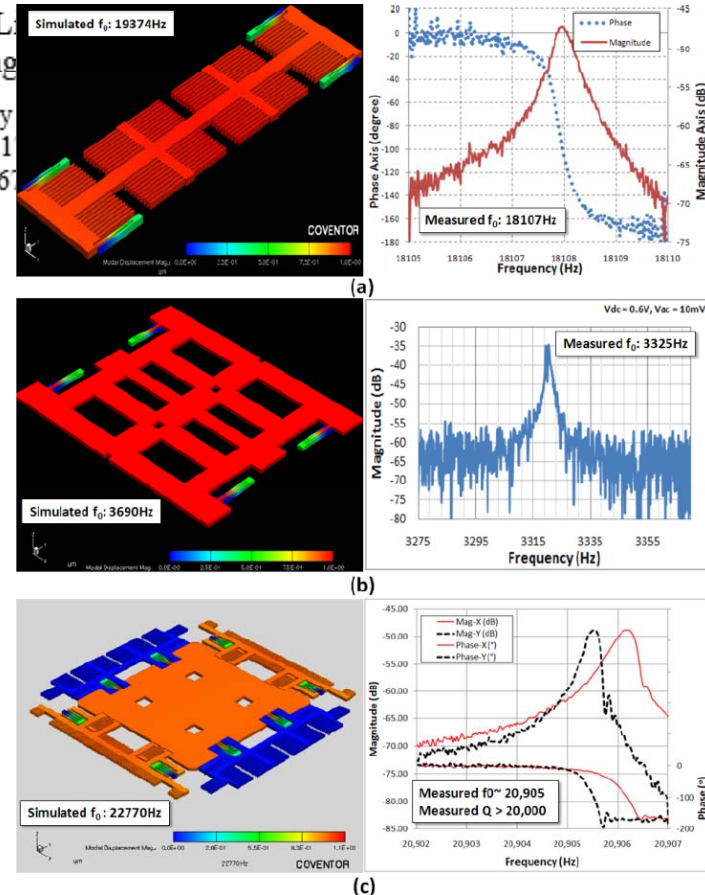


Figure 6: Comparison of measured and simulated resonance frequencies. (a) Magnetometer measured 18.1kHz and simulated 19.3kHz. (b) Accelerometer measured 3.3kHz and simulated 3.6 kHz. (c) Gyroscope measured 20.9kHz and simulated 22.7kHz.

CoventorWare Live Demo, A Gyroscope Example

The logo for CoventorWare, featuring the word "COVENTOR" in a blue, sans-serif font inside a blue rectangular box with rounded corners.

Material & Process

Layout

Preprocessor

Modal Analysis

MEMS Design Automation

Design cycle time is unacceptable

- New concept to production often takes years

Designers lack MEMS-specific software automation

- General-purpose FEA does not address MEMS multi-physics
- General-purpose FEA is too slow and does not link to EDA flow

Redundancy of modeling effort

- MEMS designers create an FEA model of their device
- ... then IC Designers need a SPICE/Verilog-A model of the MEMS
- ... then System Designers need a MATLAB model of the MEMS
- ... the list goes on for packaging, testing, failure analysis, etc.

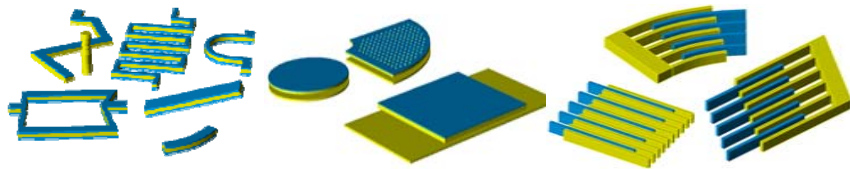
Build-and-Test fab cycles are long and wasteful

- Inadequate tools for MEMS process development

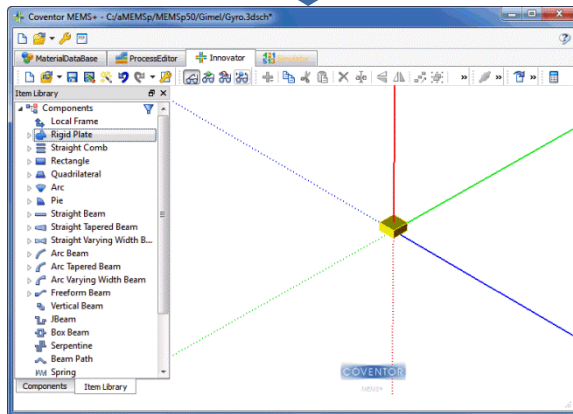
MEMS+ High-Order FEA

COVENTOR

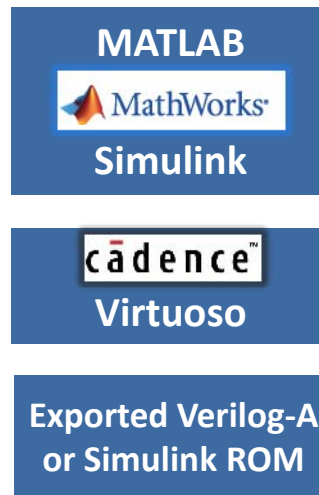
MEMS+ library of
high-order finite elements



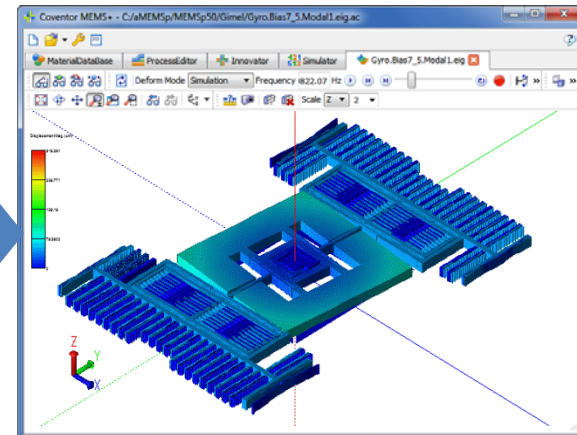
Typically 100X faster
than conventional FEA



Enter Design



Simulate



Visualize Results

Customer Publication with MEMS+



UVM-SystemC-AMS based Framework for the Correct by Construction Design of MEMS in their Real Heterogeneous Application Context

Torsten Maehne*, Zhi Wang*, Benoît Vernay*†, Liliana Andrade*, Cédric Ben Aoun*, Jean-Paul Chaput*, Marie-Minerve Louërat*, François Pêcheux*, Arnaud Krust†, Gerold Schröpfer†, Martin Barnasconi‡, Karsten Einwich§, Fabio Cenni¶, and Olivier Guillaume¶

*Sorbonne Universités, UPMC Univ Paris 06, CNRS UMR 7606, LIP6, Paris, France

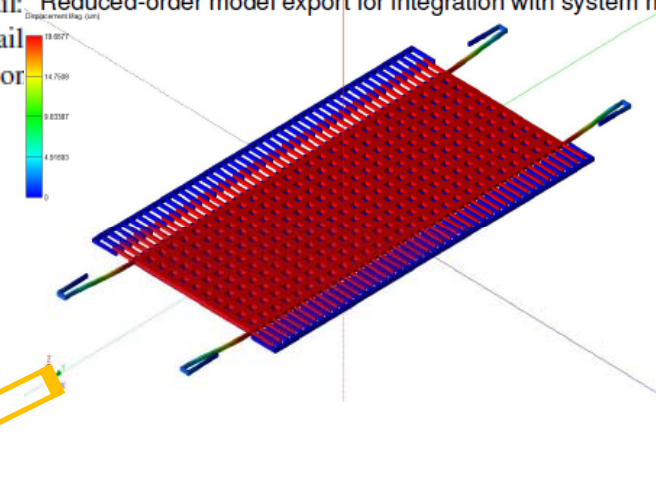
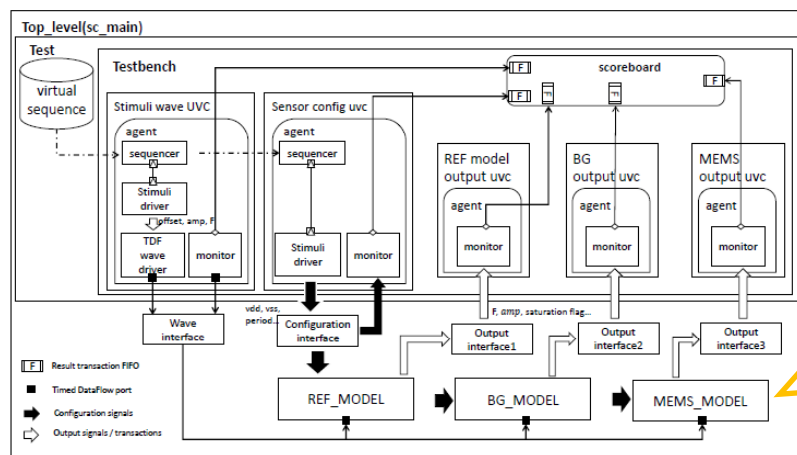
WWW: <http://www-soc.lip6.fr/>, E-mail: Torsten.Maehne@lip6.fr

†Coventor, Villebon sur Yvette, France, WWW: <http://www.coventor.com/>, E-mail: Zhi.Wang@coventor.com

‡NXP B.V., Eindhoven, The Netherlands, WWW: <http://www.nxp.com/>, E-mail: Gerold.Schroepfer@nxp.com

§Fraunhofer IIS/EAS, Dresden, Germany, WWW: <http://www.eas.iis.fraunhofer.de/>, E-mail: Martin.Barnasconi@iis.fraunhofer.de

¶STMicroelectronics (Grenoble) SAS, Grenoble, France WWW: <http://www.st.com>



Electronics, Circuits and Systems (ICECS), 2014 21st IEEE International Conference on.

Figure 2. The complete UVM-SystemC-AMS testbench for the vibration sensor MEMS with refined scoreboarding.

***MEMS+* Live Demo, A Gyroscope example**

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Material & Process

Innovator Model

Modal Analysis

Model Export for Matlab Simulink

Model Export for Cadence Virtuoso

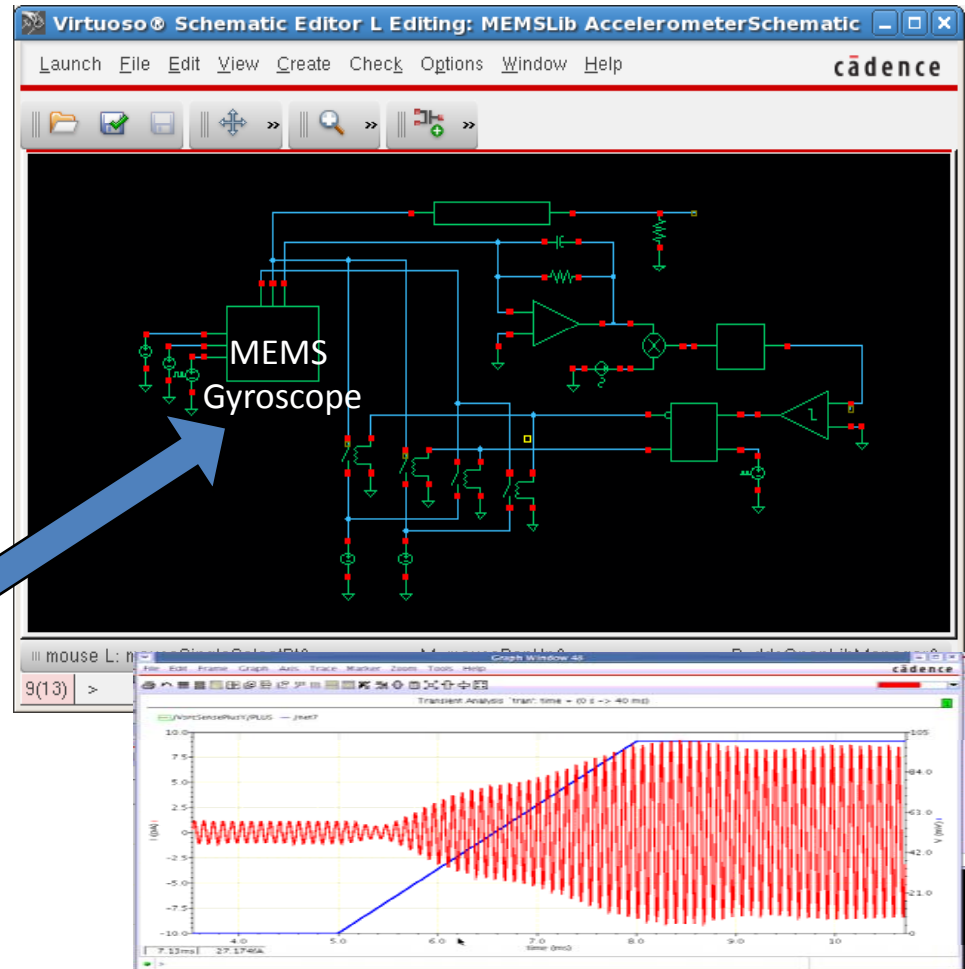
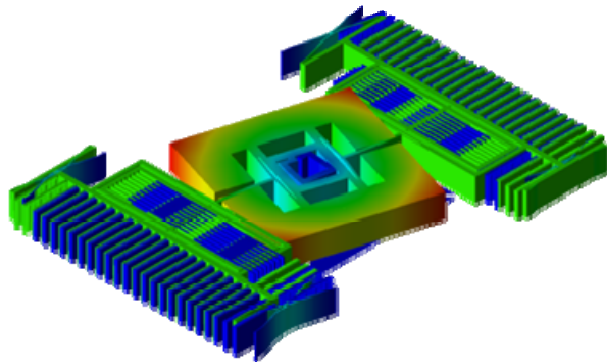
IC Designers need MEMS models for circuit design



Import a *MEMS+* model to a Cadence Virtuoso schematic

- Include all essential nonlinearities
- Selectively linearize for speed

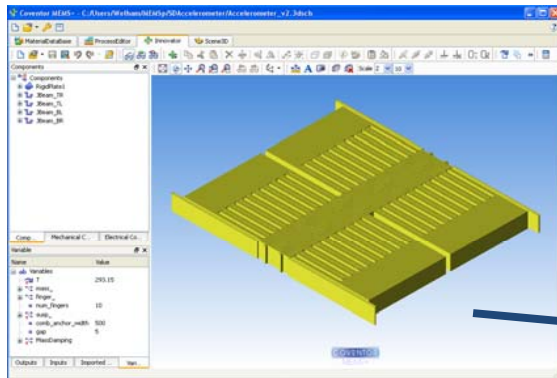
MEMS+ model of Murata Oy gyroscope



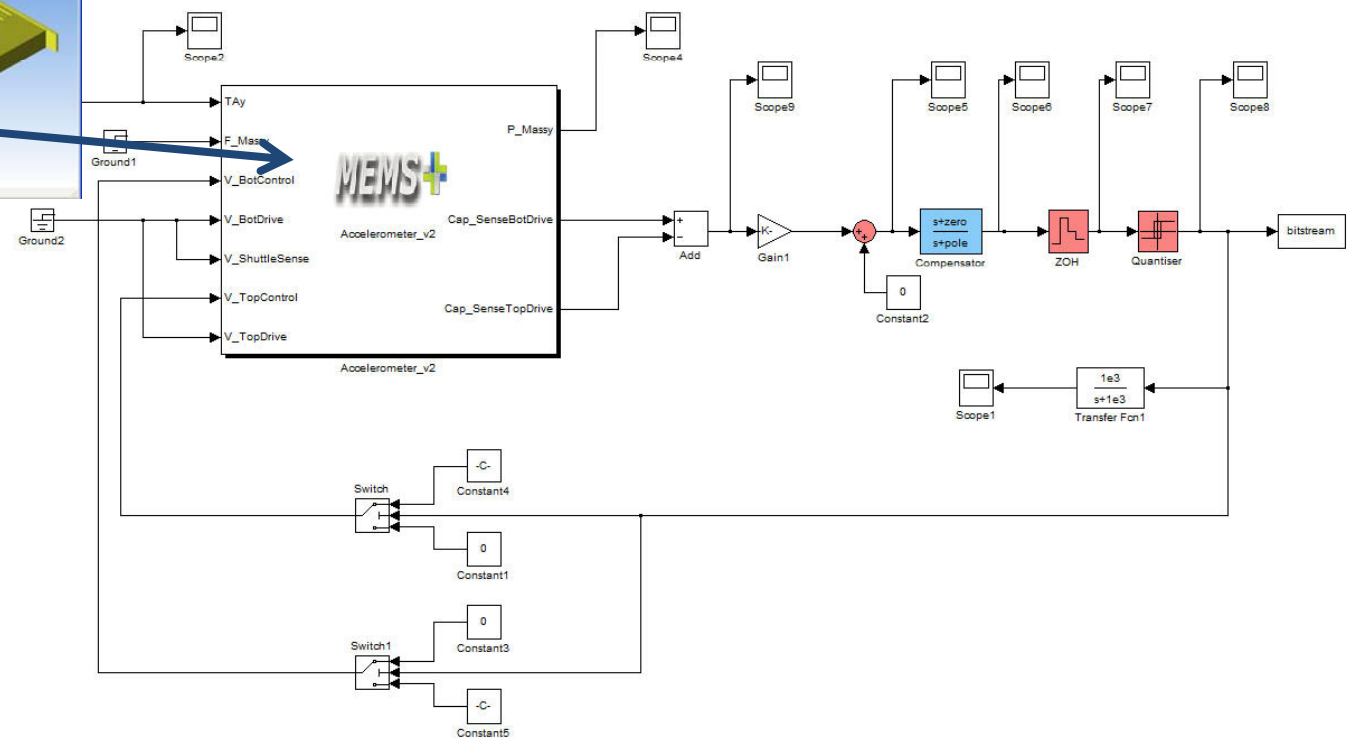
System Designers need MEMS models in MATLAB Simulink

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3D accelerometer design in MEMS+



Simulink diagram: accelerometer with sigma-delta controller



MEMS+ models
plug into Simulink

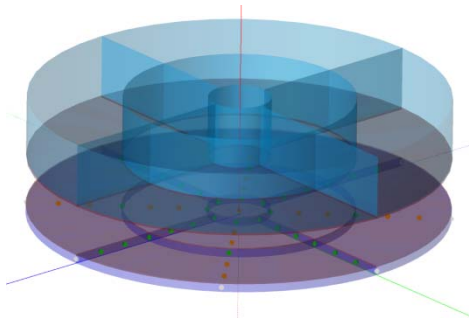
- Non-linear
- Parametric
- Fast and accurate

System Design Goal: Maximize S/N Ratio

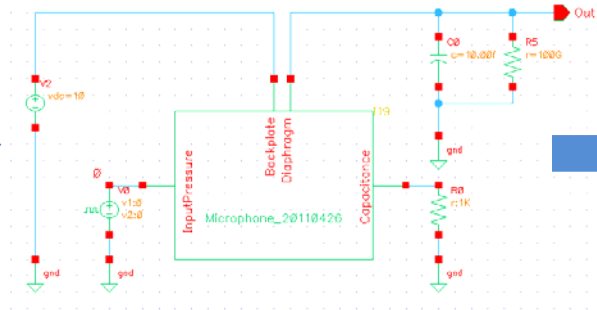


- *MEMS+* models support noise analysis in Cadence Spectre and accurately predict thermo-mechanical noise
- *MEMS+* includes all relevant noise sources in your MEMS+IC system, enabling you to evaluate noise reduction strategies

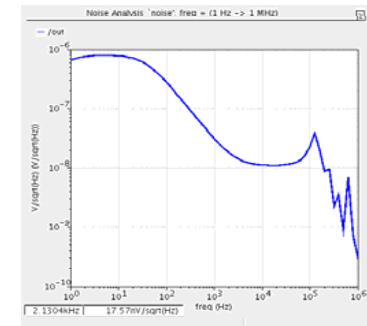
MEMS+ model of a microphone



MEMS+ model includes mechanics, electrostatics and fluidics (air pressure) effects



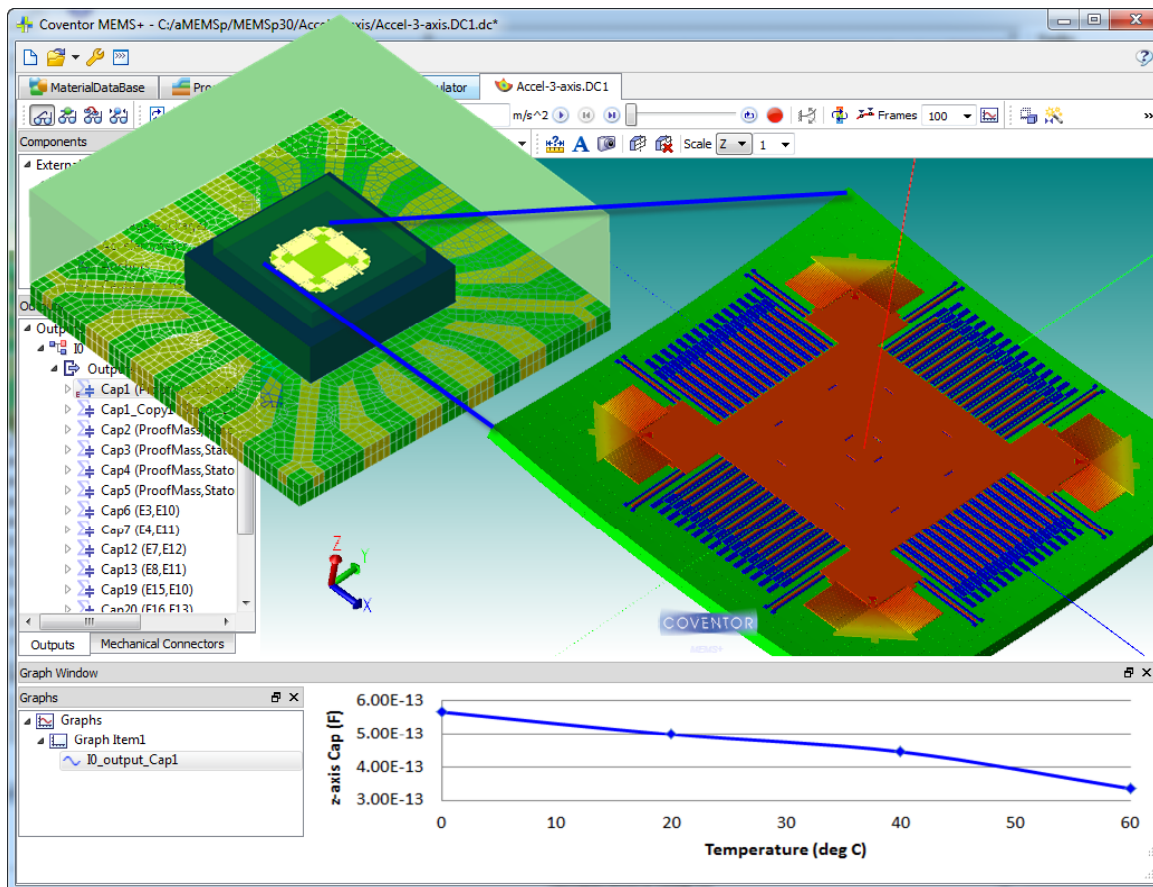
MEMS+ symbol in a Cadence Virtuoso schematic



Noise analysis in Cadence Spectre

Sensor Design Goal: Minimize thermal effects

COVENTOR



MEMS+ can predict how thermal effects on your package will affect critical sensor outputs such as zero-offset in accelerometers

Simulated zero-offset vs. temperature for z-axis of 3-axis accelerometer

MEMS+ Automatically Generates Reduced Order Models (ROMs)

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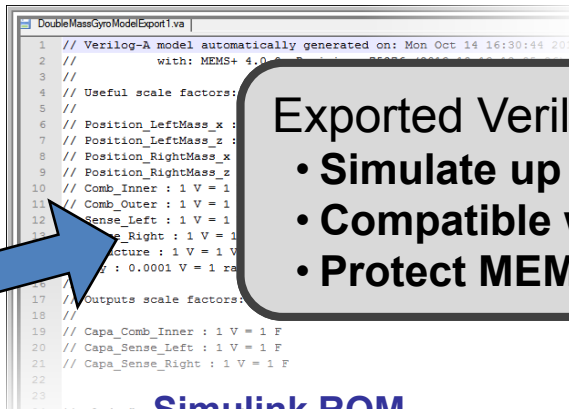
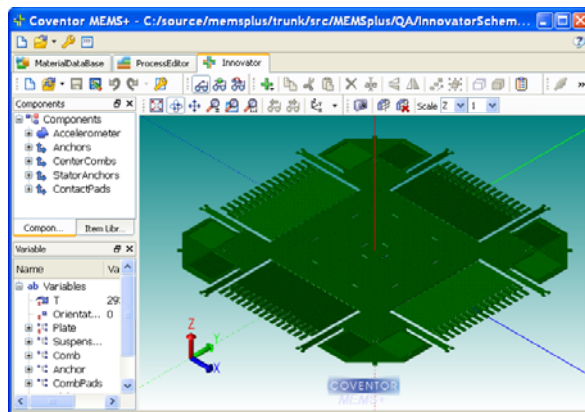
Nonlinear reduced-order model (ROM) export for very fast (100X) system simulations

Verilog-A ROM

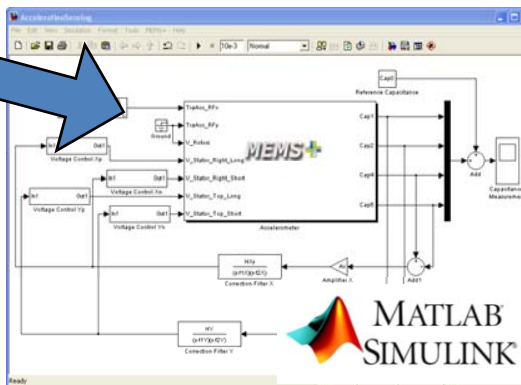
Exported Verilog-A ROMs

- Simulate up to 100X faster
- Compatible with most A/MS simulators
- Protect MEMS design IP

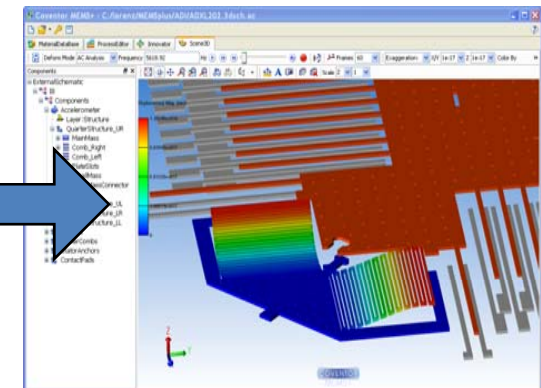
MEMS+ User Interface



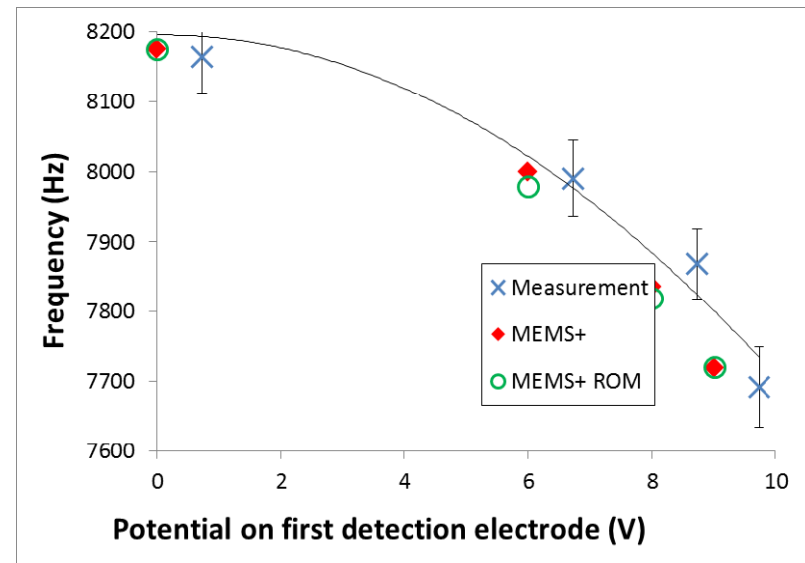
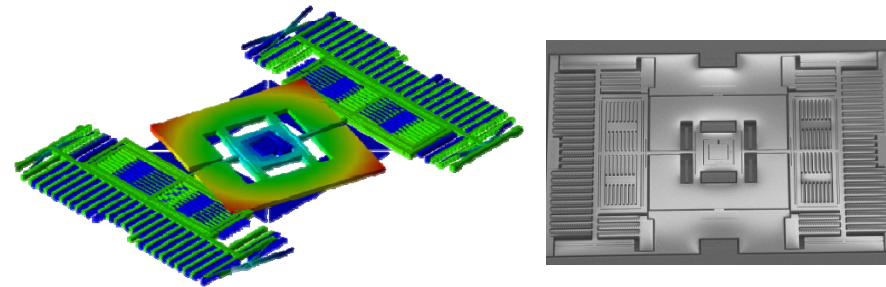
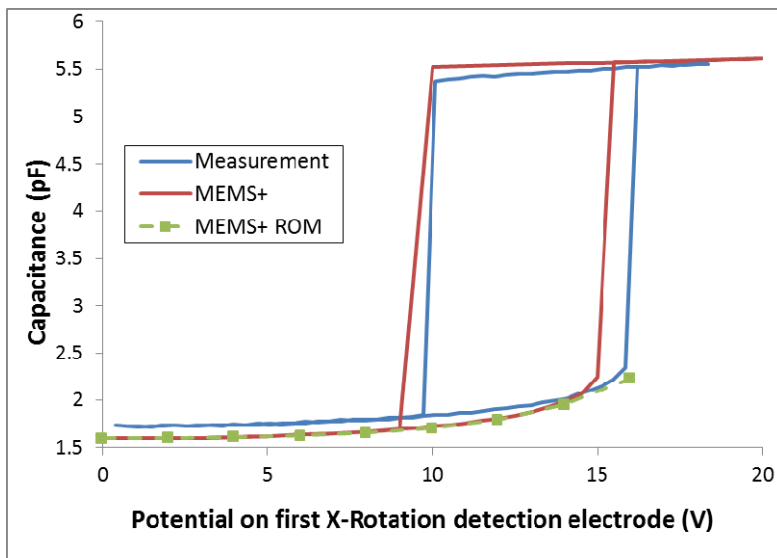
Simulink ROM



MEMS+ Result visualization



Murata 3-Axis Gyro, full MEMS+ model and exported ROM



A NOVEL MODEL ORDER REDUCTION APPROACH FOR GENERATING EFFICIENT NONLINEAR VERILOG-A MODELS OF MEMS GYROSCOPES
 Arnaud Parent¹, Arnaud Krust¹, Gunar Lorenz¹, and Tommi Piirainen²
¹Coventor sarl., France and ²Murata Electronics Oy, Finland

Tero Sillanpää, ASIC Design Manager, Murata Oy:

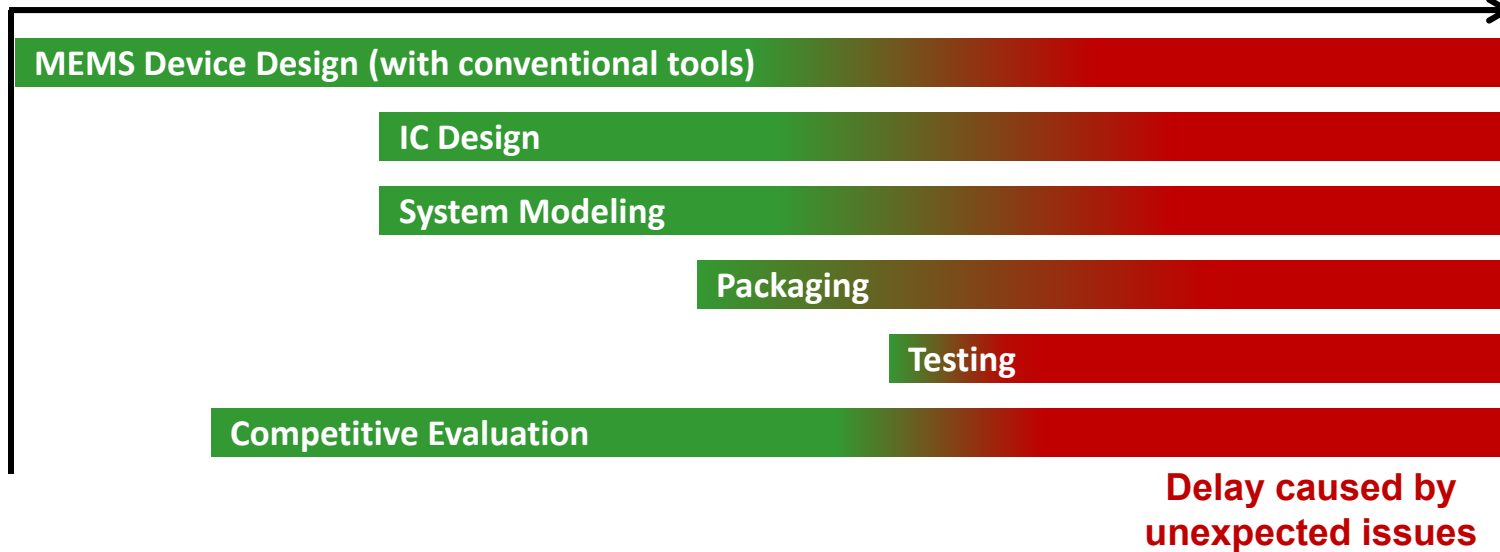
“The Verilog-A Reduced Order Model (ROM) exported from *MEMS+* 4.0 captures second order effects not seen in basic hand-crafted models without any compromise in simulation performance. We were able to create a Verilog-A ROM of a complex gyro design in just a few minutes, allowing our ASIC team to work in parallel with the MEMS team on further design iterations. Harmonic simulations in Cadence showed that the model maintained the expected modal frequencies and was stable. Moreover, transient startup simulations were very fast, on the order of 25s CPU time for 1s real time, before front-end electronic components including RC parasitic were added. The robust model exchange between MEMS and ASIC designers enabled by *MEMS+* reduces the probability of design error and can help avoid costly redesign iterations needed to address unexpected behavior.”

Exported Verilog-A models have significant advantages over hand-crafted models

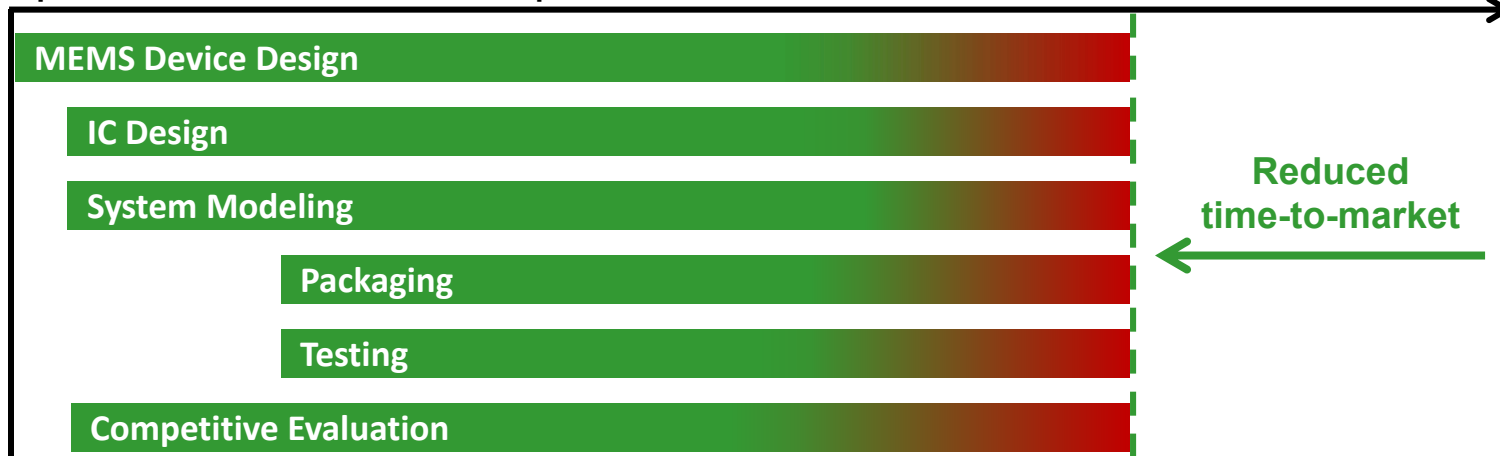
MEMS+ Enables Co-Design, Provides “Big Picture” Up Front

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Conventional MEMS Development



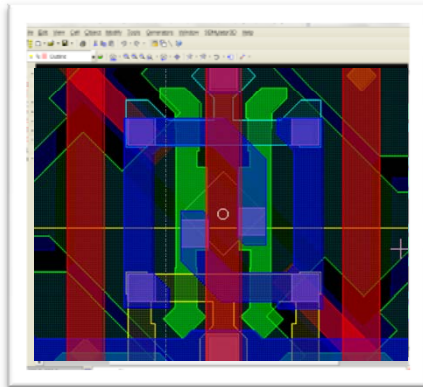
Optimized MEMS Development with MEMS+



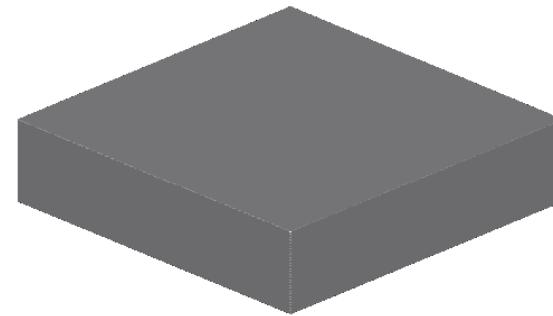
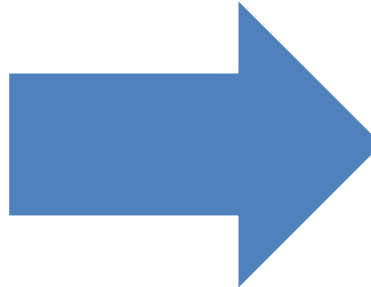
Virtual Fabrication

SEMulator3D™ Virtual Fabrication Platform

COVENTOR



Design Data:
GDS2



Process:
Behavioral Description

3D Structural Model

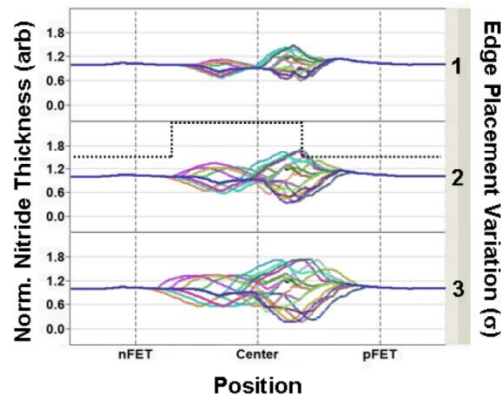
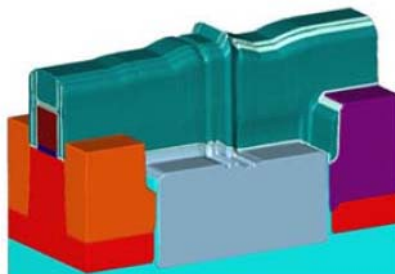
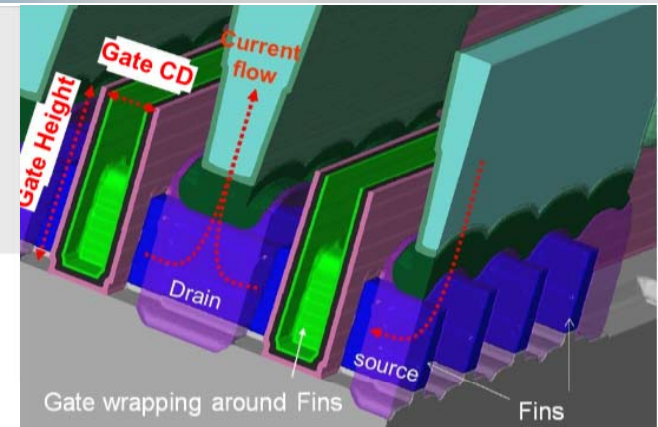
- Handles complete process sequences and large areas
- Provides 3D structural models that are **accurate**, not idealized
- Provides **predictive** insights on design/technology interactions

Customer Publication with SEMulator3D



Cpk Based Variation Reduction: 14nm FinFET Technology

Rohit Pal, Alex Chen, Xing Zhang, Sruthi Muralidharan, Laks Vanamurthy, Girish Bohra, Chloe Yong, Mitsuhiro Togo, Changyong Xiao, Si-Gyung Ahn, Yuan-Hung Liu, Puneet Khanna, Dinesh Koli, Zhe Chen, Owen Hu, Karen Riding, Manfred Eller, Rick Carter, Srikanth Samavedam



22nm Technology Yield Optimization Using Multivariate 3D Virtual Fabrication

B. Cipriany*, B. Jagannathan, G. Costrini, A. Noemaun, K. Onishi, S. Narasimha, B. Zhang, C. Sheraw, J. Meiring, M. Kumar, K. Nummy, N. Zhan, H. Nanjundappa, J. Norum, S. Furkay, R. Malik, P. Agnello
 IBM Semiconductor Research & Development Center
 Hopewell Junction, NY, US
 *brcipria@us.ibm.com

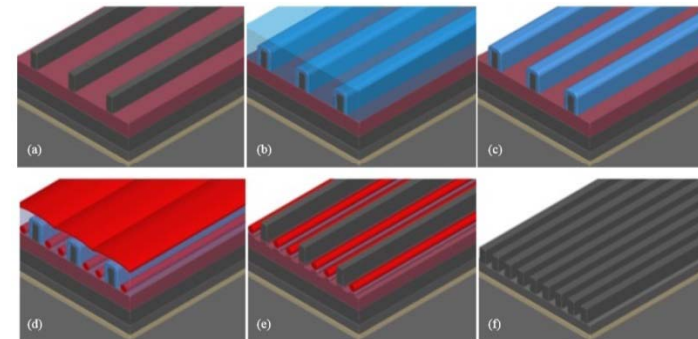
D. Fried†, K. Greiner, D. Faken, S. Breit
 Coventor, Inc.
 Cambridge, MA, US
 †david.fried@coventor.com



A comparison of the pattern transfer of line-space patterns from graphoepitaxial and chemoepitaxial block co-polymer directed self-assembly



Dan B. Millward*^a, Gurpreet S. Lugani^a, Ranjan Khurana^a, Scott L. Light^a, Ardavan Niroomand^b, Phillip D. Hustad*^c, Peter Trefonas^c, Shih-Wei Chang^c, Christopher N. Lee^c, Dung Quach^c,
^aMicron Technology, Inc., 8000 S. Federal Way, Boise, ID 83707, USA;
^bMicron Technology, Inc. Belgium; Kapeldreef 75, 3001 Leuven, Belgium;
^cDow Electronic Materials, 455 Forest St., Marlborough, MA 01752 USA;



MEMS+ Live Demo, A Gyroscope example

COVENTOR

Layout Editor

Process Creation and Calibration

Model Build

3D Viewer

Continue work: mesh export

Virtual Fabrication for MEMS Foundries

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MEMS foundries use SEMulator3D for:

- **Process development:** Predict and diagnose process issues and improve yield
- **Physical design verification:** Verify structures, release and electrical continuity before tape out
- **Customer support:** communicate process and design and information with customers
- **Failure analysis**



*"The benefits of visualizing accurate 3-D virtual MEMS prototypes include **increased probability** of achieving first-time success by minimizing analysis errors, **increased design efficiency** by identifying process errors early, avoiding undesired effects that would have reduced yield, and more **efficient communication** between design engineers and outside groups."*



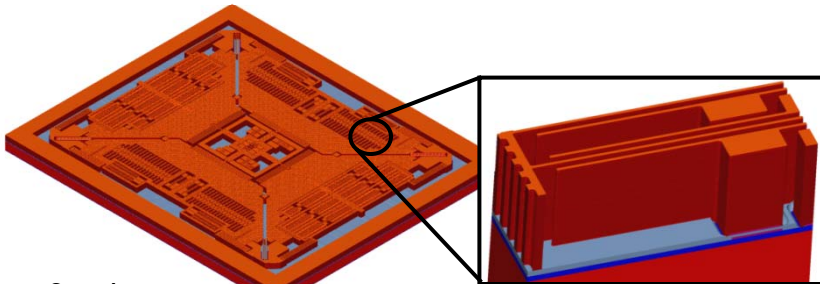
*"SEMulator3D gives engineers the ability to do virtual test runs to verify that a device design is compatible with the manufacturing process, and that the **3D result is as expected**. Design mistakes and shortcomings can be identified, even if they are compatible with 2D layout rules."*



Virtual Fabrication: Uses for MEMS



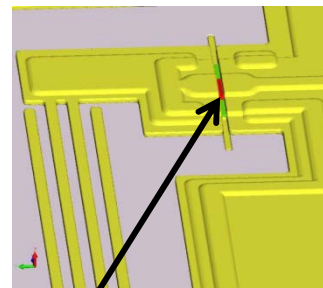
Communication: Visualize, Animate process, Designers \leftrightarrow Fab/Foundry, Tech transfer



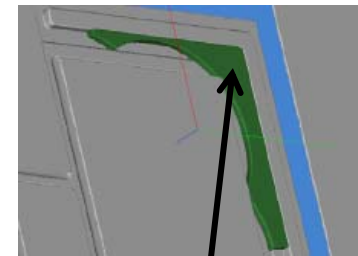
3-axis gyro from chipworks teardown

View details, cross section

Physical Verification: Check structures, release completion, electrical continuity

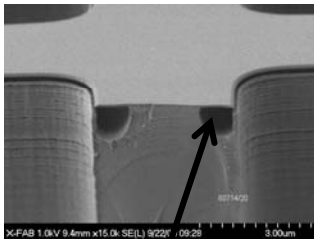


Design error passed 2D DRC

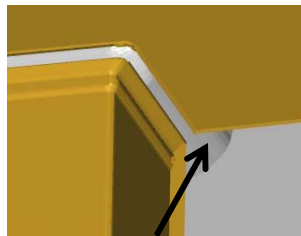


Incomplete release etch

Process Development: Predict/diagnose process problems

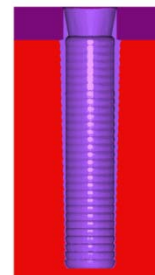


Issue: unexpected voids

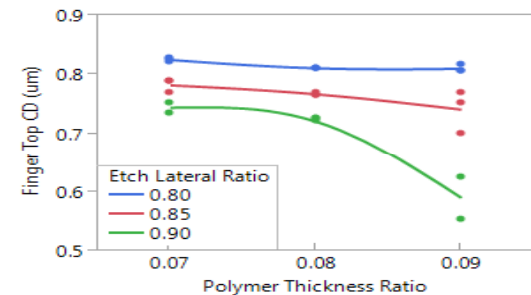


SEMulator3D model confirms root cause

Yield Optimization:



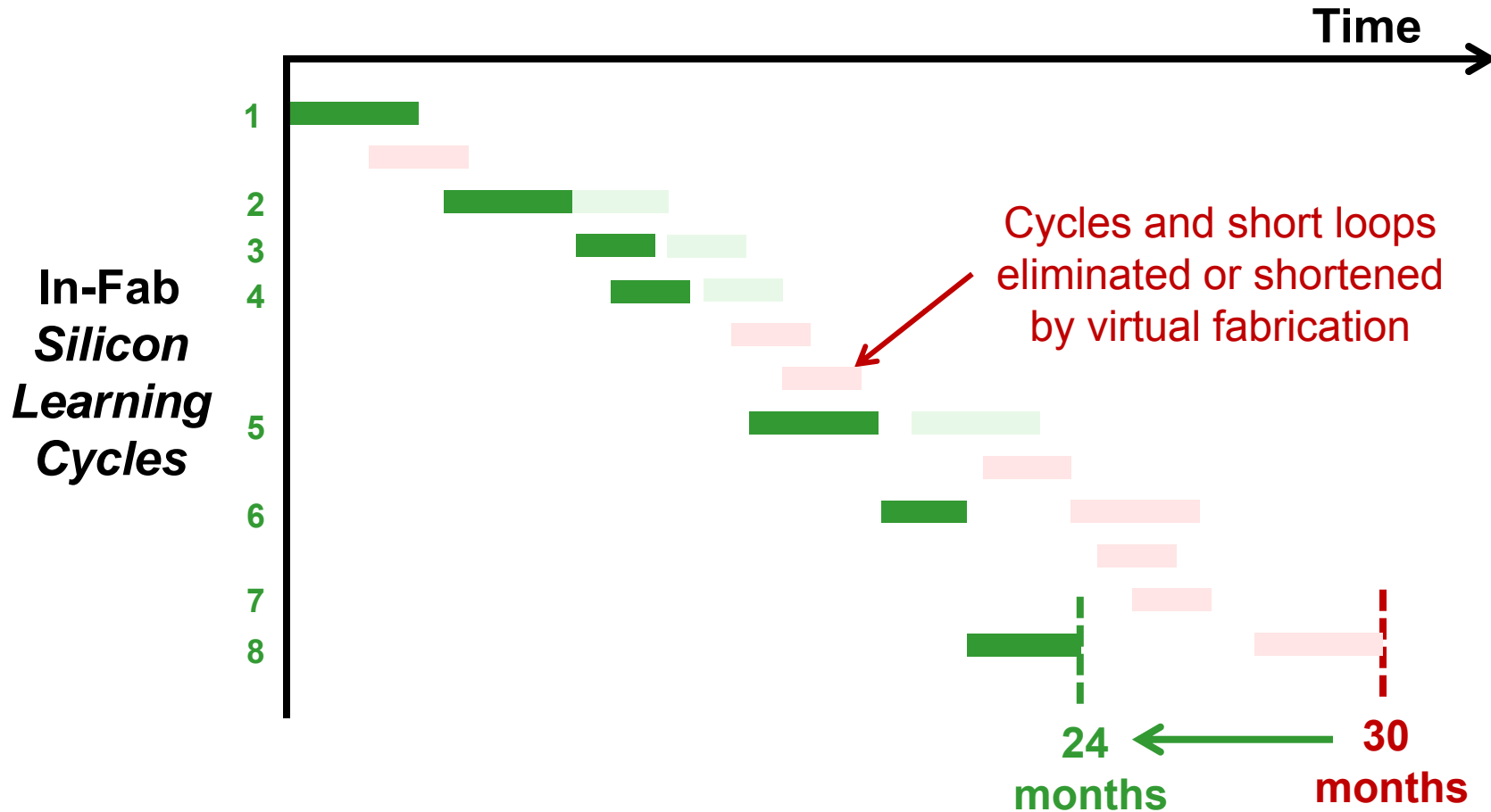
DRIE



Quantify sensitivity of structure CDs to process parameters

Benefit of Virtual Fabrication for MEMS Development

COVENTOR



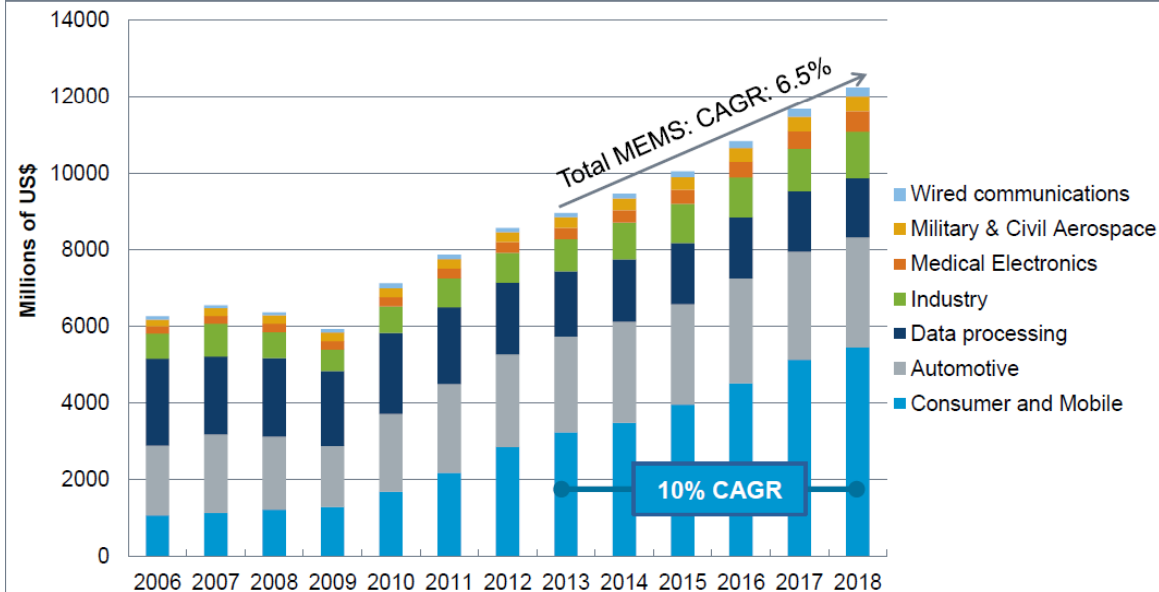
Virtual Learning optimizes Silicon Learning and can significantly **shorten time-to-market**

Conclusion

High growth Big opportunities

COVENTOR

Total MEMS market by applications



Source: IHS – MEMS Market Tracker – Q4 2014

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Examples:

- 9 DOF Integration, IME
- pMUT (Piezoelectric Micromachined Ultrasonic Transducers) for fingerprint sensors, UC Berkeley

Coventor is the “de facto” MEMS design automation leader

Coventor enables:

Time-to-Market Reduction

Risk Mitigation

Project Cost Reduction

How?

- **SEMulator3D** Virtual Fabrication
- **MEMS+** “High-Order FEA”
- **CoventorWare** Hybrid FEM/BEM